



SAN 10/820,911

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Michael E. Littau et al. Examiner: Gordon J. Stock, Jr.
Serial No.: 10/820,911 Group Art Unit: 2877
Filed: April 08, 2004 Docket: 31162-1011
Title: Determination of Center of Focus by Parameter Variability Analysis

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

In compliance with the duty imposed by 37 C.F.R. § 1.56, and in accordance with 37 C.F.R. §§ 1.97 *et. seq.*, the referenced materials are brought to the attention of the Examiner for consideration in connection with the above-identified patent application. Applicants respectfully request that this Information Disclosure Statement be entered and the documents listed on the attached Form 1449 be considered by the Examiner and made of record. Pursuant to the provisions of MPEP 609, Applicants request that a copy of the 1449 form, initialed as being considered by the Examiner, be returned to the Applicants with the next official communication.

Pursuant to 37 C.F.R. § 1.97(c)(2), Applicants have included the fee of \$180.00 as set forth in 37 C.F.R. § 1.17(p). Please charge any additional fees or credit any overpayment to Deposit Account No. 13-4213.

The Examiner is invited to contact the Applicants' Representative at the below-listed telephone number if there are any questions regarding this communication.

In accordance with the waiver of 37 C.F.R. § 1.98(a)(2)(i) for submitting a copy of each cited U.S. patent and publication for all U.S. national patent applications filed after June 30, 2003, only copies of the foreign references and other documents are enclosed.

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Title: Determination of Center of Focus by Parameter Variability Analysis

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Dkt: 31162-1011

Respectfully submitted,

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By their Representatives,

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Date March 8, 2005

By 

Stephen A. Slusher
Reg. No. 43,924

CERTIFICATE UNDER 37 CFR 1.8: The undersigned hereby certifies that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail, in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on this 8th day of March, 2005.

Stephen A. Slusher, Reg. No. 43,924
Name



Signature



Substitute for form 1449A/PTO

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**
(Use as many sheets as necessary.)

Complete if Known

Application Number	10/820,911
Filing Date	April 8, 2004
First Named Inventor	Littau, Michael
Group Art Unit	2877
Examiner Name	Gordon J. Stock, Jr.

Sheet 1 of 2

Attorney Docket No: 31162-1011

US PATENT DOCUMENTS

Examiner Initial *	USP Document Number	Publication Date	Name of Patentee or Applicant of cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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EXAMINER**DATE CONSIDERED**

Substitute Disclosure Statement Form (PTO-1449)

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.
 1 Applicant's unique citation designation number (optional) 2 Applicant is to place a check mark here if English language Translation is attached



PTO/SB/08A (08-03)
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Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)		Complete if Known	
		Application Number	10/820,911
		Filing Date	April 8, 2004
		First Named Inventor	Littau, Michael
		Group Art Unit	2877
		Examiner Name	Gordon J. Stock, Jr.
Sheet 2 of 2		Attorney Docket No: 31162-1011	

FOREIGN PATENT DOCUMENTS					
Examiner Initials*	Foreign Document No	Publication Date	Name of Patentee or Applicant of cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ²
	WO-WO 01/97279 A2	12/20/2001	Miller, Michael L., et al.		
	WO-WO 03/032085	04/17/2003	Littau, Michael E., et al.		

OTHER DOCUMENTS -- NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
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EXAMINER

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